

Application/Control No.	Applicant(s)/Patent under Reexamination
10/089,319	AURES ET AL.
Examiner	Art Unit
John L. Shew	2616

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	229,230	7/19/2006	JS
	230.1		
	231,232		
	233,234		
	235,236		
	395.2		
	395.3		
	395.41		
	468,539		
	541		
379	142.03	7/19/2006	JS
	211.01		
	212.01		
	230		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY	7)
	DATE	EXMR

Search Notes (continued)

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	SEAR	CHED	
Class	Subclass	Date	Examiner
379	265.01	7/19/2006	
	266.04		,
	309		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SEAR	CHSTRATEGY	)
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